Correction to: Influence of Cu incorporation on ionic conductivity and dielectric relaxation mechanism in NiO thin films synthesized by CBD

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The original version of this article contained an error in figure.

Figure 11 was inadvertently submitted wrongly and published in the original article. The corrected version of Fig. 11 is given below. The figure caption will remain the same as in the original article. This has been corrected with this erratum.

The original article can be found online at <https://doi.org/10.1007/s10854-017-8024-x>.

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Fig. 11 The frequency spectra of imaginary part of electric modulus at different temperature for **a** NiO; **b** 7% Cu:NiO; frequency spectra of imaginary part of electric modulus for all the films at a fixed temperature 320 °C shown in **c**